

<b>Notice of References Cited</b>	Application/Control No. 10/736,605	Applicant(s)/Patent Under Reexamination HIROSE ET AL.	
	Examiner Thien F. Tran	Art Unit 2811	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-			
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	C	US-			
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**FOREIGN PATENT DOCUMENTS**

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**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Liu et al., "Ni and Ni silicide Schottky contacts on n-GaN", Journal of Applied Physics, Vol. 84, No. 2, pp 881-886, July 15, 1998
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
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